

### Amendments to the Claims

This listing of claims will replace all prior versions, and listings, of claims to the application:

#### Listing of Claims

Claim 1 (currently amended): A method of ~~inspecting~~ finding the depth of a hole in an etched layer in a semiconductor substrate sample using a charged-particle beam, comprising the steps of:

irradiating the hole with the charged-particle beam, ~~the hole being formed in an etched layer on a substrate forming a sample to be inspected;~~

detecting an electric current flowing between the ~~inspected~~ substrate sample and ground as a result of the irradiation; and

finding the etch depth of said hole ~~into~~ in the substrate ~~of the inspected sample, based on a previously found relation of the current flowing between holes in a reference sample and ground to the etch depths of the holes into the substrate, the relation being previously found using the in said reference sample.~~

Claim 2 (currently amended): A method of inspecting a hole in an etched layer in a semiconductor substrate sample using a charged-particle beam, comprising the steps of:

irradiating the hole with the charged-particle beam, ~~the hole being formed in an etched layer on a substrate forming a sample to be inspected;~~

detecting an electric current flowing between the inspected sample and ground as a result of the irradiation; and

finding how the hole in the inspected sample is etched, based on previously found relations of the current flowing between holes in a reference sample and ground ~~to etch~~

~~depths of holes into the substrate and~~ to remaining film thickness in the holes, ~~the relations~~  
~~being previously found using the in said~~ reference sample.

Claim 3 (currently amended): A method of ~~inspecting~~ finding the depth of a  
hole ~~using a charged particle beam~~ as set forth in claim 1, further including the steps of:

previously finding a relation of electric current flowing between the reference  
sample and ground to etch depths of holes into the substrate, using the reference sample;

previously classifying these etch depths into plural groups; and

finding to which of the groups ~~does~~ the currently inspected etch depth ~~belong~~  
belongs, based on the detected electric current flowing between the inspected sample and  
ground.

Claim 4 (currently amended): A method of inspecting a hole ~~using a charged-~~  
~~particle beam~~ as set forth in claim 2, further including the steps of:

previously finding a relation of electric current flowing between the reference  
sample and ground to etch depths of holes or a relation of electric current flowing between  
the reference sample and ground to remaining film thicknesses in the holes;

previously classifying these etch depths or remaining film thicknesses into  
plural groups; and

finding to which of the groups ~~does~~ the currently inspected etch depth ~~belong~~  
belongs, based on the detected electric current flowing between the inspected sample and  
ground.

Claim 5 (cancelled)

Claim 6 (cancelled)

Claim 7 (currently amended): A method of inspecting a hole using in an etched layer in a semiconductor substrate sample a charged-particle beam, comprising the steps of:

irradiating the hole with the charged-particle beam,~~the hole being formed in an etched layer on a substrate forming a sample to be inspected;~~

detecting an electric current flowing between the inspected substrate sample and ground as a result of the irradiation;

comparing the detected electric current with an electric current that is previously found using a reference sample ~~and~~ flowing between the reference sample and ground where the hole is precisely etched; and

judging that the hole in the inspected sample is precisely etched if the two currents agree, that the hole is overetched if the detected electric current is greater than the previously found current, and that the hole is underetched if the detected current is smaller than the previously found current.

Claim 8 (cancelled)

Claim 9 (cancelled)

Claim 10 (currently amended): A method of ~~inspecting~~ finding the depths of holes in an etched layer in a semiconductor substrate sample using a charged-particle beam, comprising the steps of:

irradiating a region containing the holes with the charged-particle beam,~~the holes being formed in an etched layer on a substrate forming a sample to be inspected;~~

detecting an electric current flowing between the inspected sample and ground as a result of the irradiation;

repeating these steps for plural regions previously established on the inspected sample;

obtaining data about a distribution of etch depths of the holes in the inspected sample ~~into~~ in the substrate, based on the detected current and on a previously found relation of detected current flowing between the reference sample and ground to etch ~~depth~~ depths of the ~~hole~~ holes into the substrate, ~~the relation being previously found using the reference sample;~~ and

displaying a map based on the obtained data about the distribution of etched depths on a display unit.

Claim 11 (currently amended): A method of inspecting holes using a charged-particle beam as set forth in claim 10, wherein said map is displayed with different symbols ~~or different pieces of information~~, in different colors, or with different brightness levels.

Claim 12 (currently amended): A method of inspecting holes using a charged-particle beam as set forth in claim 11, wherein said different symbols ~~or different pieces of information~~ are characters.

Claim 13 (currently amended): A method of ~~inspecting~~ finding the depths of holes in an etched layer in a semiconductor substrate sample using a charged-particle beam, comprising the steps of:

irradiating a region containing the holes with the charged-particle beam, ~~the holes being formed in an etched layer on a substrate forming a sample to be inspected;~~

detecting an electric current flowing between the inspected sample and ground as a result of the irradiation;

repeating these irradiating and detecting steps for plural regions previously established on the inspected sample;

obtaining data about a distribution of etch depths of the holes in the inspected sample ~~into~~ in the substrate, based on the detected current and on a previously found relation of electric current flowing between a reference sample and ground to etch depths of the holes into the substrate and also on a previously found relation of the electric current flowing between the reference sample and ground to remaining film thicknesses in the holes; and

displaying a map on a display unit, based on data obtained about the distribution of degrees of etching in the holes in the inspected sample.

Claim 14 (currently amended): A method of inspecting holes using a charged-particle beam as set forth in claim 13, wherein said map is displayed with different symbols ~~or different pieces of information~~, in different colors, or with different brightness levels.

Claim 15 (currently amended): A method of inspecting holes using a charged-particle beam as set forth in claim 14, wherein said different symbols ~~or different pieces of information~~ are characters.

Claim 16 (currently amended): A method of inspecting holes using a charged-particle beam as set forth in any one of claims ~~10-15~~ 13-15, wherein each of said plural regions is so selected that plural holes are contained therein.

Claim 17 (currently amended): A method of inspecting holes using a charged-particle beam as set forth in any one of claims ~~10-15~~ 13-15, wherein said plural regions illuminated with said charged-particle beam are selected to be in certain positions within a periodic pattern formed on said sample.

Claim 18 (currently amended): A method of inspecting holes using a charged-particle beam as set forth in any one of claims ~~10-15~~ 13-15, wherein each of said plural regions is totally scanned with said charged-particle beam in a scanning period, said electric

current is accumulated during the scanning period, and an obtained accumulated value is used as a measurement value about each region.

Claim 19 (currently amended): A method of inspecting holes using a charged-particle beam as set forth in any one of claims ~~10-15~~ 13-15, wherein each of said plural regions is totally scanned with said charged-particle beam in a scanning period, an average value of said current over the scanning period is taken, and said average value is used as a measurement value about each region.

Claim 20 (currently amended): A method of inspecting holes using a charged-particle beam as set forth in any one of claims ~~10-15~~ 13-15, wherein each of said plural regions is totally irradiated with said charged-particle beam without scanning of the beam in an irradiation period, said electric current is accumulated during the irradiation period, and an obtained accumulated value is used as a measurement value about each region.

Claim 21 (currently amended): A method of inspecting holes using a charged-particle beam as set forth in any one of claims ~~10-15~~ 13-15, wherein each of said plural regions is totally irradiated with said charged-particle beam without scanning of the beam in an irradiation period, an average value of said current over the irradiation period is taken, and said average value is used as a measurement value about each region.

Claim 22 (original): A method of inspecting holes using a charged-particle beam, comprising the steps of:

preparing a reference sample precisely etched;

preparing an unknown sample that is not known whether it has been etched precisely or not;

irradiating a region of said reference sample containing holes with the charged-particle beam;

detecting an electric current flowing between the reference sample and ground;

repeating these irradiating and detecting steps for plural preselected regions on said reference sample;

irradiating a region of said unknown sample containing holes with the charged-particle beam;

detecting an electric current flowing between the unknown sample and ground;

repeating these irradiating and detecting steps for plural preselected regions on said unknown sample;

finding data about current distributions on the reference sample and on the unknown sample;

creating graphs indicative of the characteristics of the currents flowing through the regions of the reference sample and unknown sample; and

displaying said graphs side by side on a display unit.

Claim 23 (original): A method of inspecting holes using a charged-particle beam as set forth in claim 22, wherein said graphs indicative of the characteristics are formed by plotting detected current values in increasing order, from their minimum values.

Claim 24 (original): A method of inspecting holes using a charged-particle beam as set forth in claim 22, wherein said graphs indicative of the characteristics are formed by plotting detected current values in decreasing order, from their maximum values.